Product Cycle and Role of Analysis





Plasticity and Creep Modeling (Thermal Loading)



Mechanical Loading





Solder Deformation Caused by Mechanical Loading



Laboratory for Optomechanics and Micro/nano Semiconductor/Photonics Systems

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Global/Local Modeling Approach





PCT Simulation for COF



Moisture Diffusion Analysis









Slice model to simulate delamination at NCP/chip & NCP/PI tape interfaces during PCT (121°C/95%RH/196hrs)

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Simulation of Vertical Drop Test (Dynamic Modeling)





Vertical Drop Deformation Analysis

- Strain Distribution within Critical Solder Ball -





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Thermal Conduction Model (HP-LED)





Thermal Convection Model - 40" PDP Module-



